

The Making of LaB₆ Crystals

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The following image is of a LaB₆ crystal formation created at the FEI Company, Hillsboro, Oregon. The photograph was taken through a Bausch & Lomb Stereo Zoom 4 at 30X with a Polaroid MicroCam.



The single crystal LaB_s and CeB_s is grown and fabricated at FEI using a well-defined process known as "Inert Gas Arc Float Zone Refining." This promelt the hot, pressed powder sample of LaB₆ or CeB₆. This not only allows the and 20 years of experience in the growth of rare-earth boride single crystals, for the highest possible ratio of electron emission to evaporation rate.





The LaB₆ formation shown at left is a controllable artifact that is formed at the very end of a zone refining run. The formation is created when the refined crystal above the electrode separates from the raw material below the electrode.

Features result from the recrystallization of the molten rod below the separation point. The effect depends on the way in which the molten zone is separated and on the cooling rate. The method of separation determines the amount



of material that makes up the molten volume. In practice this depends on how fast the electrode is shut off and the raw and refined material is pulled apart.

Surface tension favors a spherical shape when gravity is not significant, but if too much mass is on the molten volume, then gravity will tend to widen and flatten it - hence, the quasi-spherical or hemispherical effect. The cooling rate then determines how long impurities have to diffuse out of the hot (but cooling) LaB, and the state of the equilibrium shape when it has finally frozen. The rate of cooling determines the size of the polycrystals or grains. Polycrystal is generally a higher energy state than single crystal. So if the material cools quickly, it's likely to be polycrystal. If the material cools slowly, the result is anything from polycrystal with large grain sizes to single crystal, a lower energy state.

The hot end near the separation point takes longer to cool and the end form is cess takes place in an inert gas atmosphere and utilizes an electrical arc to a competition between the cooling, recrystallizing pure material that existed above the separation point, and the more quickly cooling, impure material below the sepagrowth of the crystal, but also helps to purify the material. Through research ration point. If the top 'cleaner' material has long enough to grow, it will attempt to form the LaB₆ <100> planes. Because it is impure though, it will have many types FEI can carefully control the material composition (e.g. stoichiometry of B/La) of flaws and defects, some which produce terraces and steps as seen in the photograph.

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Note: The Tacky Dot technology, U.S. Patent no. 5,356,751, is intended for use in microscopy laboratories. Our license to supply this technology to you does not extend beyond applications in microscopy.



Tacky Dot Slides

This innovative new technology now gives the analyst the ability to rapidly mount particles, saving valuable time.

A glass slide is covered by a pattern of fine adhesive centers. The mounting process can be as simple as dusting the sample onto the mounting media. Tapping the edge of the mounting media easily removes excess sample material. Even better results may be obtained by using the Tacky Dot Array Slide Holder, as described below.

The Tacky Dot slides are suited for 25 to 1000 µm particles.

This method gives the analyst the ability to mount clusters of two or more particles per center or mount thousands of non-touching particles, one-to-a-center, in a regular array. This new mounting medium simplifies the examination, identification and analysis of the mounted particles.

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- the ability to mount the same pattern and/or number of particles.
- the ease with which particles can be identified by coordinates and examined by multiple techniques.
- the ease in determining average weight of single particles.

Dot Size (rectangular array)	Dot Spacing (center-to-center)	SPI # pkg/10	SPI # pkg/100	SPI # pkg/500
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40µm	500µm	02386-BA	02386-MB	02386-RA
50µm	500µm	02387-BA	02387-MB	02387-RA
75µm	500µm	02388-BA	02388-MB	02388-RA
100µm	1,000µm	02389-BA	02389-MB	02389-RA
150µm	1,000µm	02390-BA	02390-MB	02390-RA
200µm	2,000µm	02391-BA	02391-MB	02391-RA
300µm	2,000µm	02392-BA	02392-MB	02392-RA
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